RAD-TOLERANT SPACE GRADE DIE, QUADRUPLE 2-INPUT POSITIVE-AND GATES

Check for Samples: SN54HC273-DIE

FEATURES

- **Wide Operating Voltage Range**
- **Outputs Can Drive Up To 10 LSTTL Loads**
- **Low Power Consumption**
- **Typical t_{pd} = 12 ns**
- **Low Input Current**
- **Contain Eight Flip-Flops With Single-Rail Outputs**
- **Direct Clear Input**
- **Applications Include:**
  - **Buffer/Storage Registers**
  - **Shift Registers**
  - **Pattern Generators**

DESCRIPTION

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not related directly to the transition time of the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output.

Table 1. FUNCTION TABLE (each flip-flop)

INPUTS			OUPUT Q
$\overline{CLR}$	CLK	D	
L	X	X	L
H	↑	H	H
H	↑	L	L
H	L	X	Q_0

ORDERING INFORMATION(1)

PRODUCT	PACKAGE DESIGNATOR	PACKAGE	ORDERABLE PART NUMBER	PACKAGE QUANTITY
SN54HC273V	TD	Bare die in waffle pack(2)	SN54HC273VTDG1	100
			SN54HC273VTDG2	10

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Processing is per the Texas Instruments space production baseline and is in compliance with the Texas Instruments Quality Control System in effect at the time of manufacture. Electrical screening consists of DC parametric and functional testing at room temperature only. Unless otherwise specified by Texas Instruments AC performance and performance over temperature is not warranted. Visual Inspection is performed in accordance with MIL-STD-883 Test Method 2010 Condition B at 75X minimum.

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

BARE DIE INFORMATION

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
10.5 mils.	Silicon with backgrind	Floating	TiW/AlCu2%	1210 nm

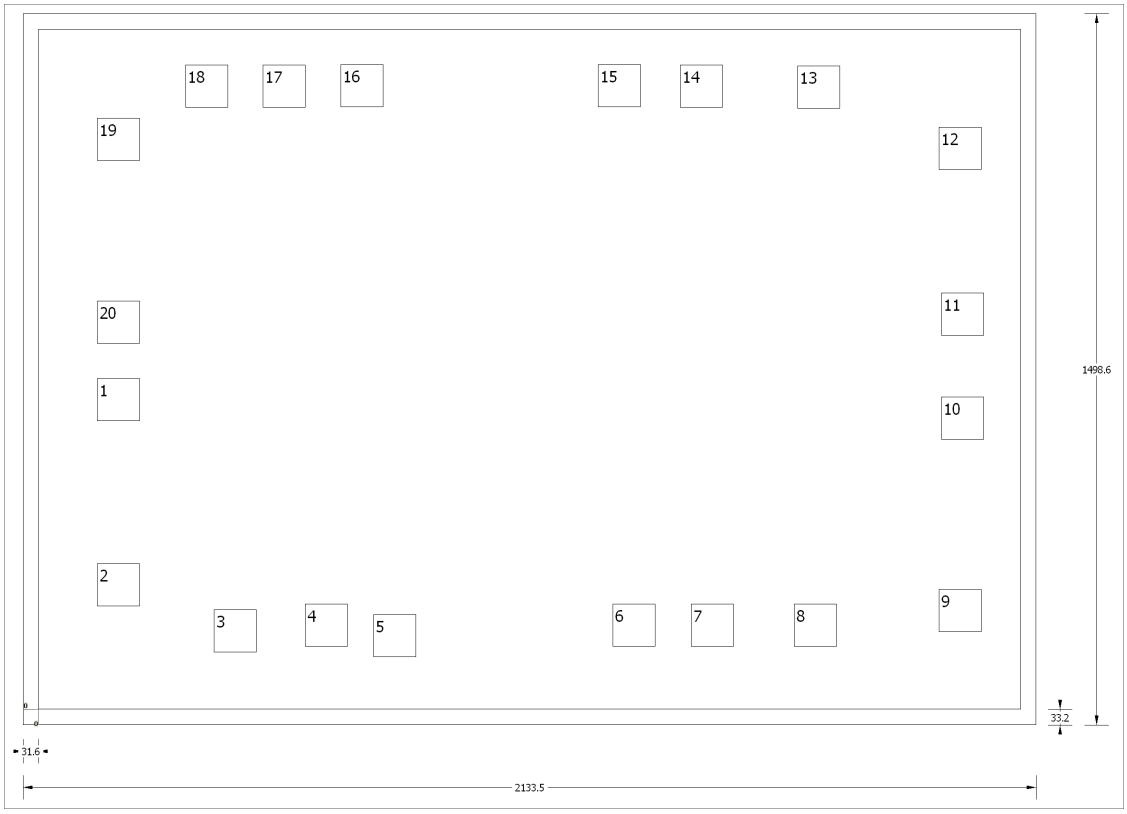

Table 2. Bond Pad Coordinates in Microns

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
CLR	1	124.05	606.65	214.05	696.65
1Q	2	124.05	216.95	214.05	306.95
1D	3	369.75	119.75	459.75	209.75
2D	4	562.35	132.35	652.35	222.35
2Q	5	706.35	109.85	796.35	199.85
3Q	6	1210.35	132.35	1300.35	222.35
3D	7	1375.05	132.35	1465.05	222.35
4D	8	1591.95	132.35	1681.95	222.35
4Q	9	1897.05	162.95	1987.05	252.95
GND	10	1901.55	567.95	1991.55	657.95
CLK	11	1901.55	786.65	1991.55	876.65
5Q	12	1897.05	1135.85	1987.05	1225.85
5D	13	1599.15	1264.55	1689.15	1354.55
6D	14	1351.65	1267.25	1441.65	1357.25
6Q	15	1178.85	1268.15	1268.85	1358.15
7Q	16	637.05	1268.15	727.05	1358.15
7D	17	473.25	1267.25	563.25	1357.25
8D	18	310.35	1267.25	400.35	1357.25
8Q	19	124.05	1154.75	214.05	1244.75
VCC	20	124.05	769.55	214.05	859.55

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN54HC273VTDG1	ACTIVE			0	100	RoHS & Green	Call TI	N / A for Pkg Type	25 to 25		Samples
SN54HC273VTDG2	ACTIVE			0	10	RoHS & Green	Call TI	N / A for Pkg Type	25 to 25		Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

OTHER QUALIFIED VERSIONS OF SN54HC273-DIE :

- Space : SN54HC273-SP

NOTE: Qualified Version Definitions:

- Space - Radiation tolerant, ceramic packaging and qualified for use in Space-based application

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Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265